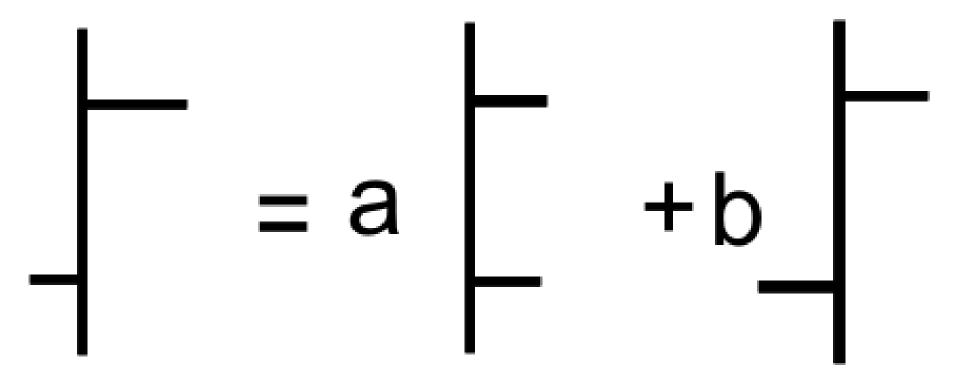
Sparse-layer Inversion Using Basis Pursuit Decomposition

John Castagna and Rui Zhang University of Houston

Alternative Seismic Inversion Philosophies

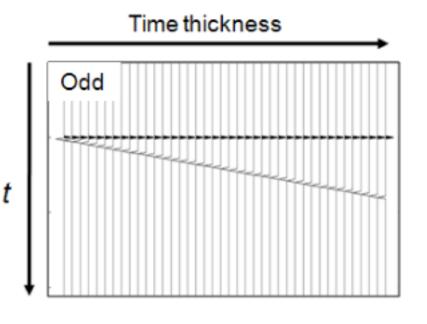
- Sparse-spike methods invert the seismic trace for a limited number of reflection coefficients.
- This limits the thin-layer resolution.
- Alternatively, we formulate the seismic inversion problem to solve for a limited number of layer impulse pairs, rather than a limited number of spikes.
- Will this improve layer resolution?

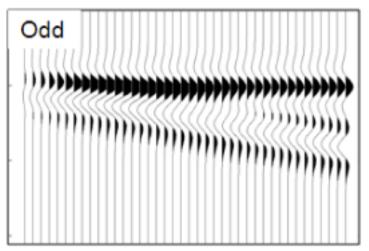
Any reflection pair can be represented as the sum of even and odd impulse pairs:

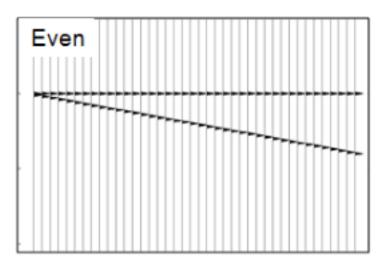


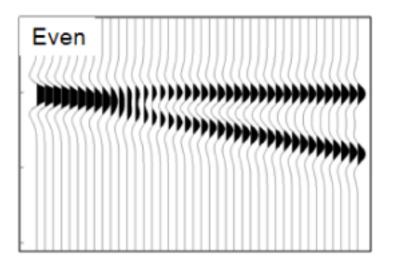
Thus: Any seismogram can be represented as the sum of even and odd responses.

Even and odd wedge dictionary elements







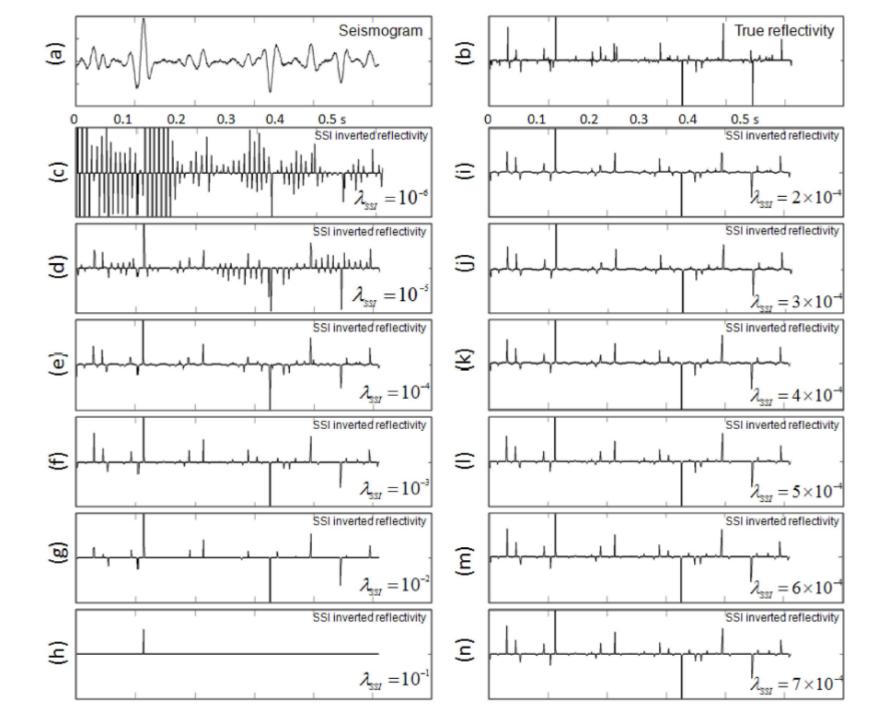


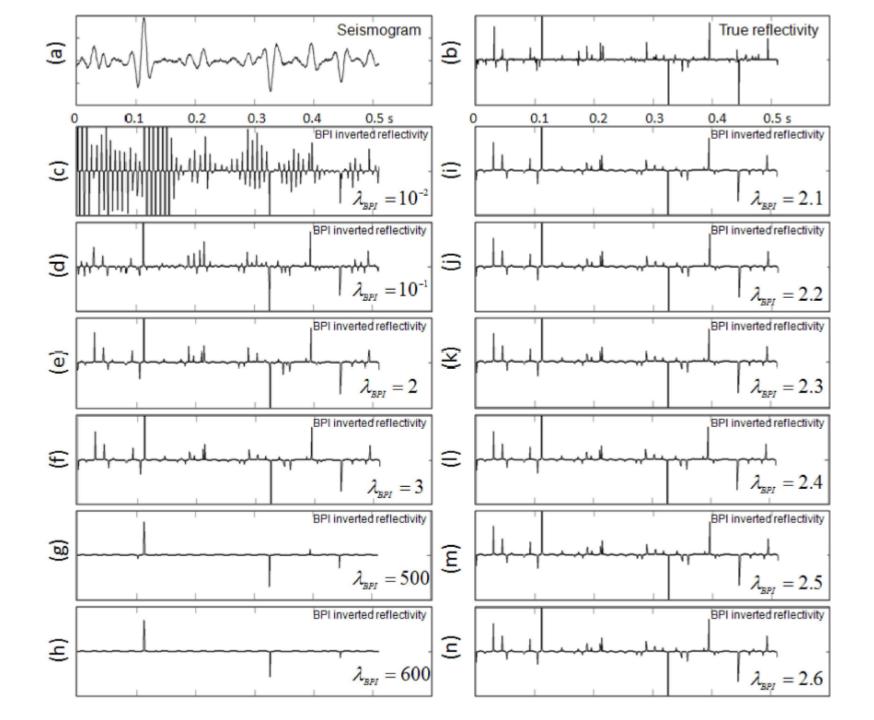
Basic Pursuit Dipole Decomposition

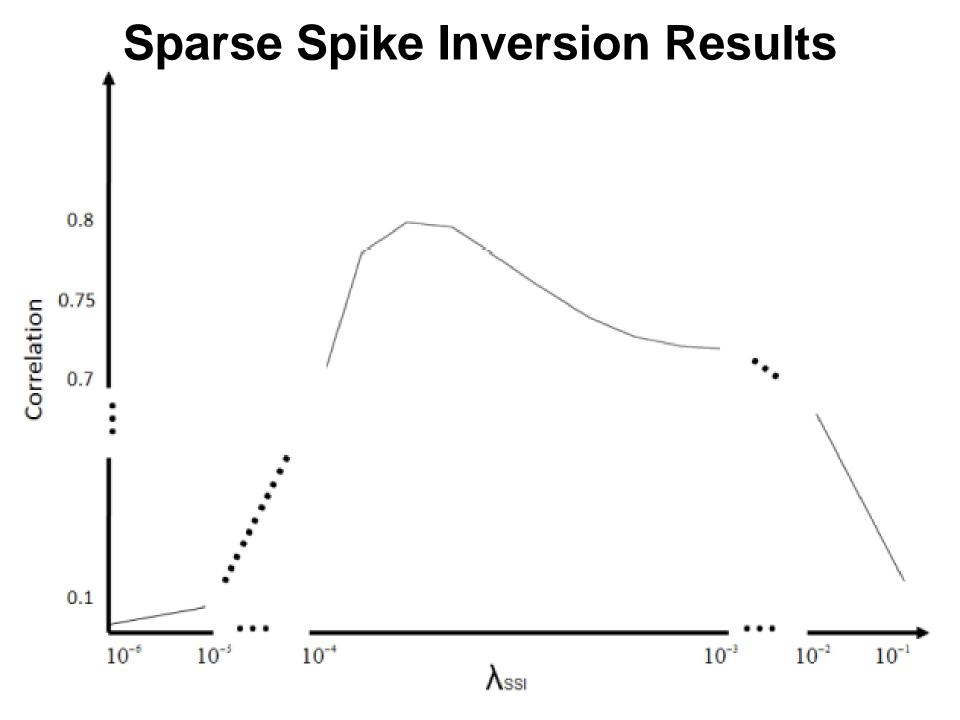
$$r(t) = \sum_{n=1}^{N} \sum_{m=1}^{M} (a_{n,m} * r_e(t, m, n, \Delta t) + b_{n,m} * r_{\mathsf{o}}(t, m, n, \Delta t))$$

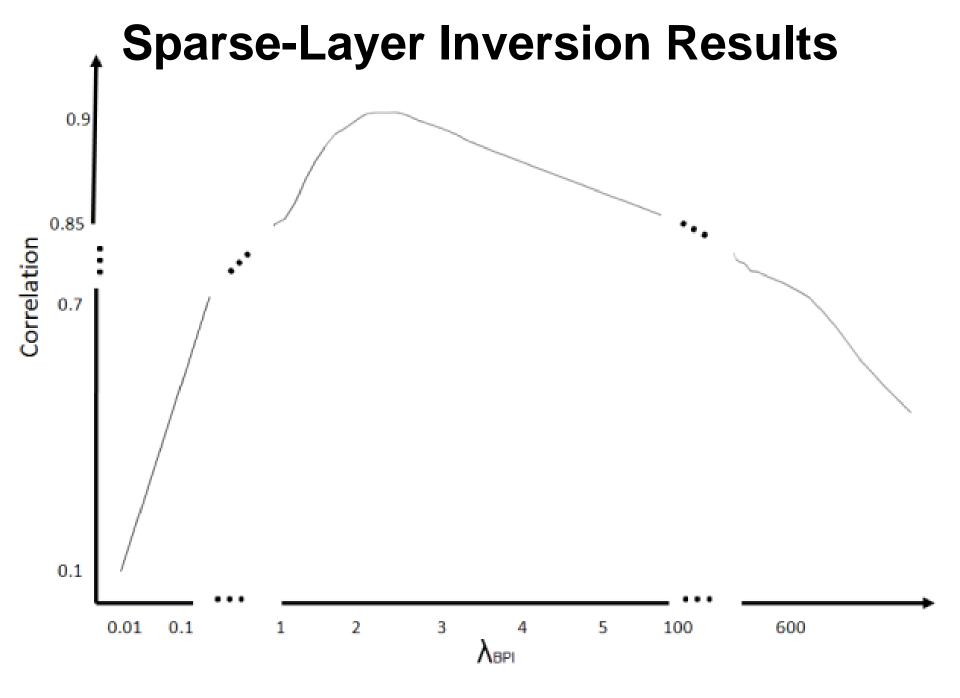
Basic Pursuit Thin-Layer Response Decomposition

$$\mathbf{s}(t) = \sum_{n=1}^{N} \sum_{m=1}^{M} (a_{n,m} * \mathbf{s}_{e}(t, m, n, \Delta t) + b_{n,m} * \mathbf{s}_{o}(t, m, n, \Delta t))$$

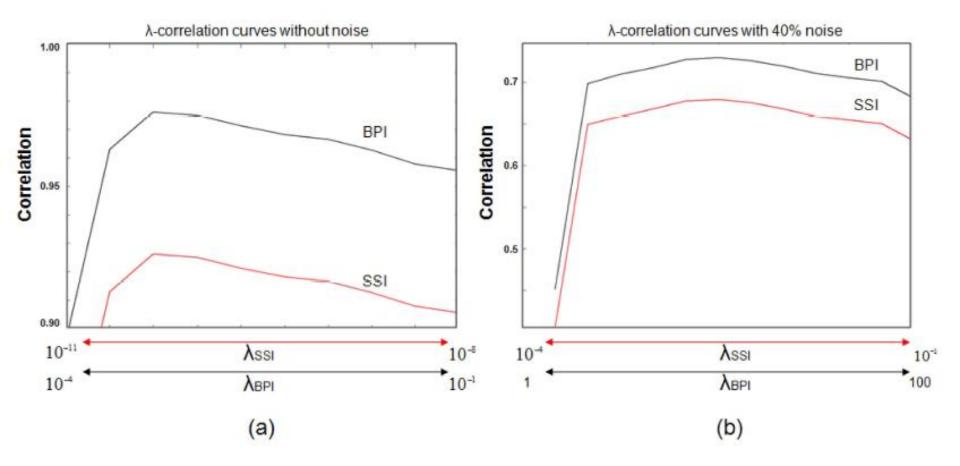


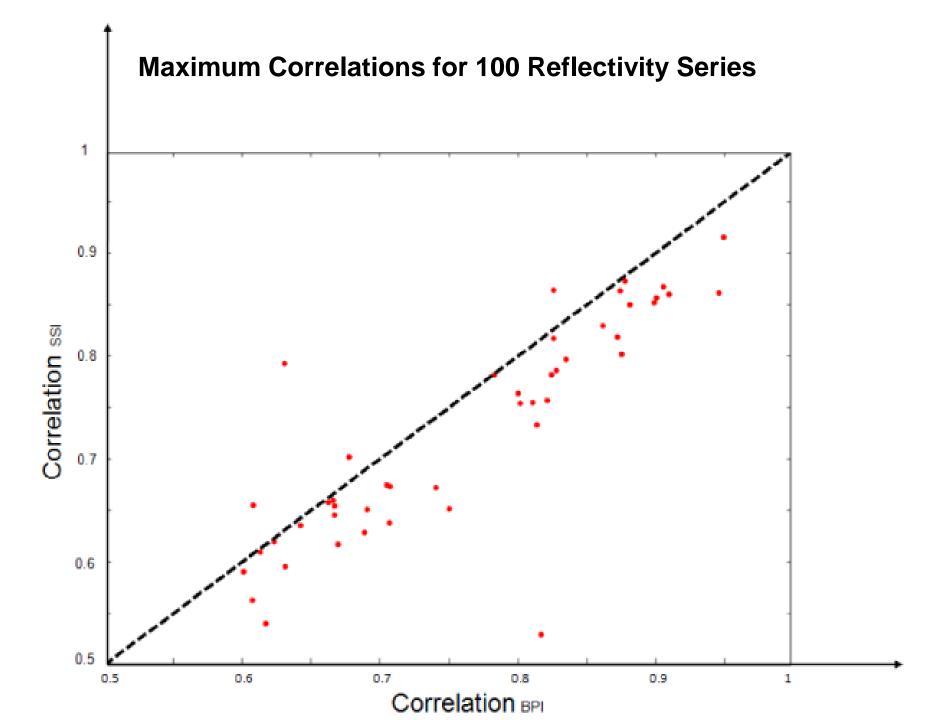


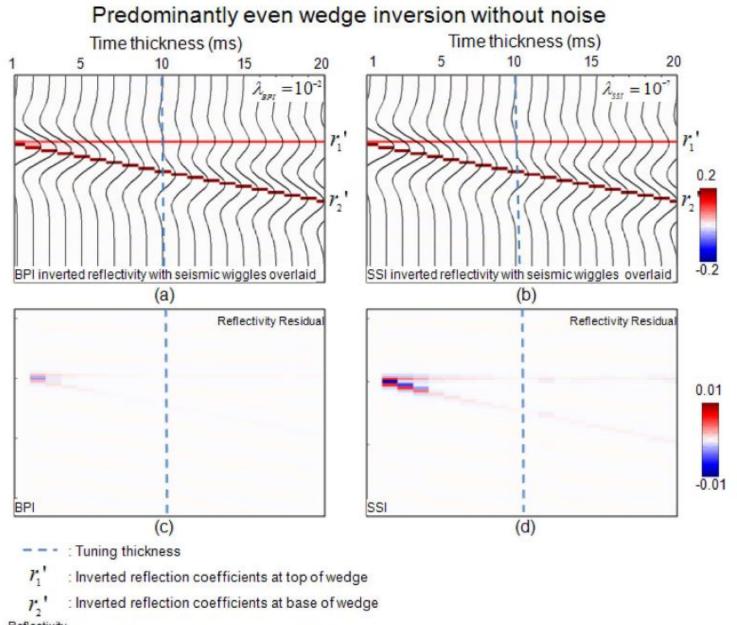




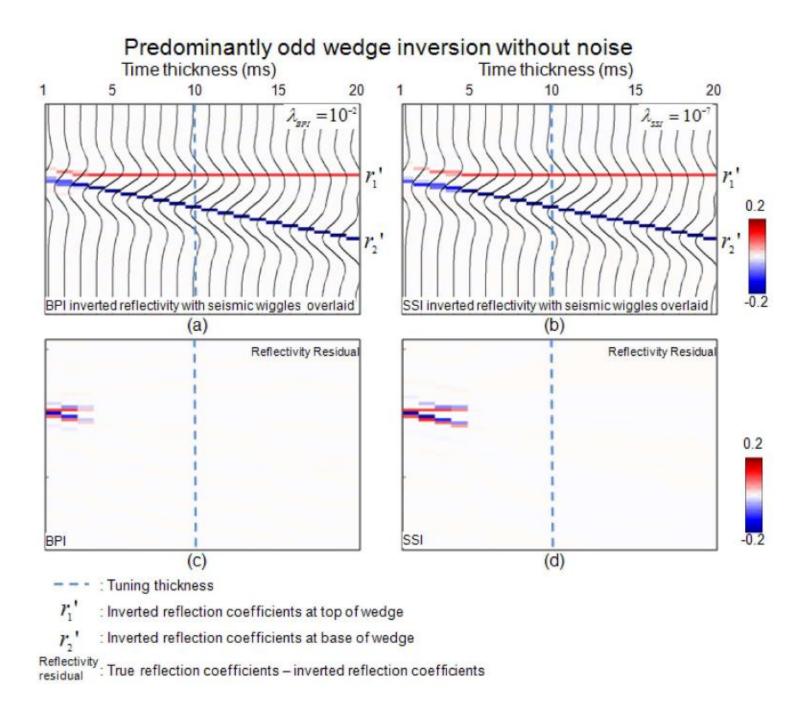
Effect Of Noise

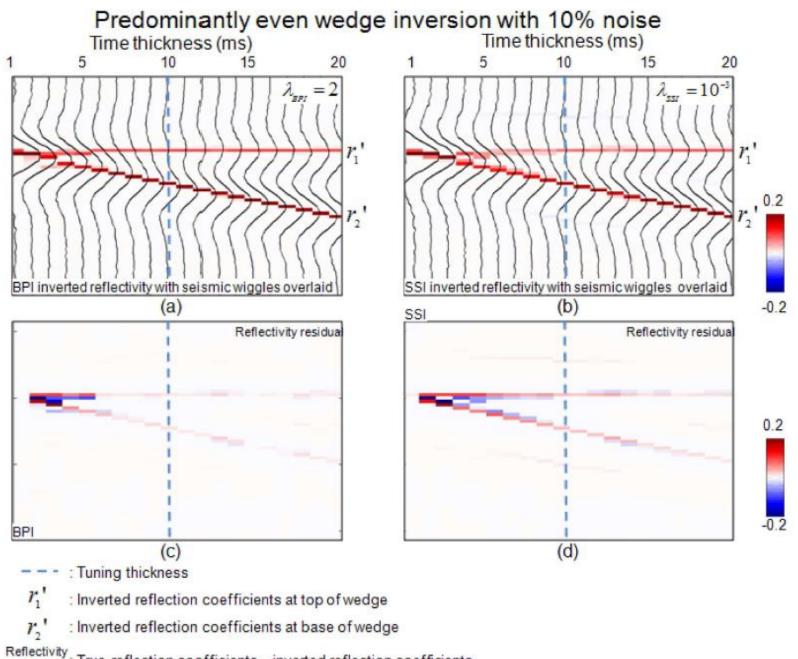




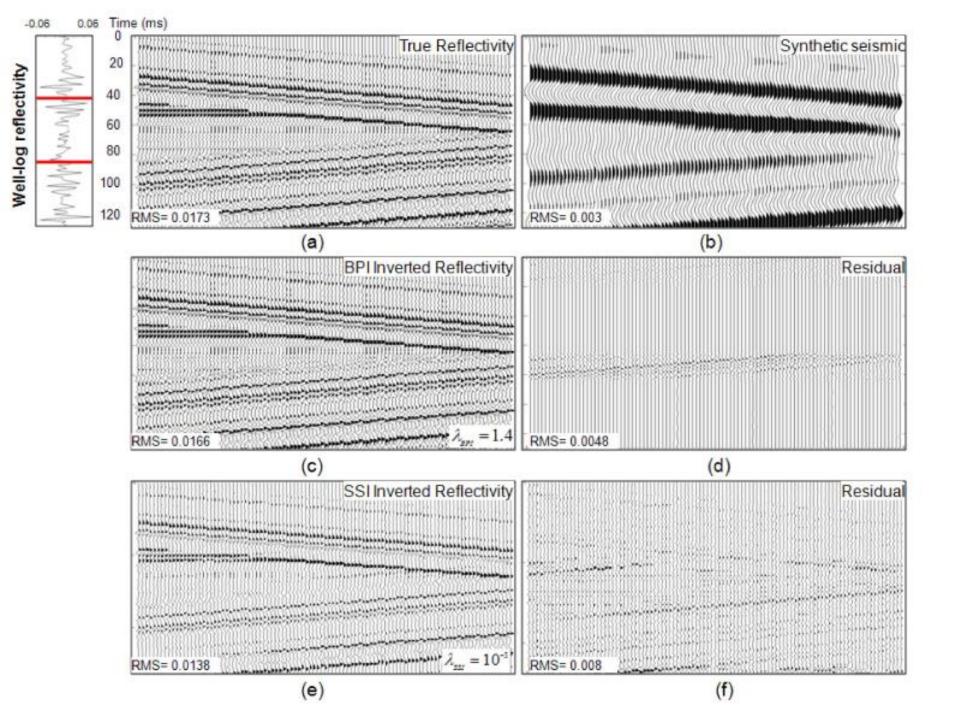


Reflectivity residual : True reflection coefficients – inverted reflection coefficients

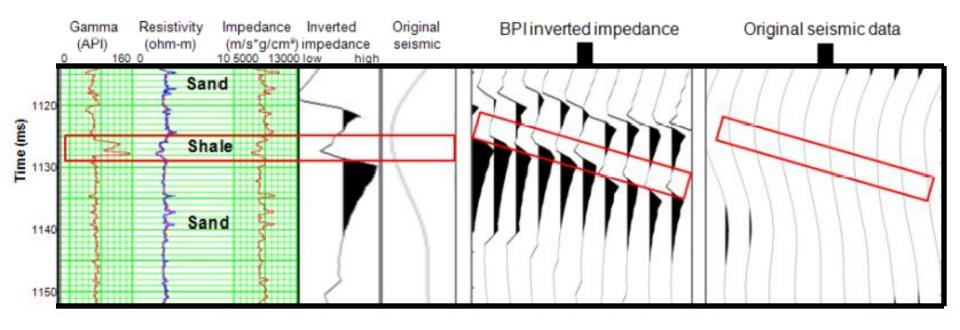




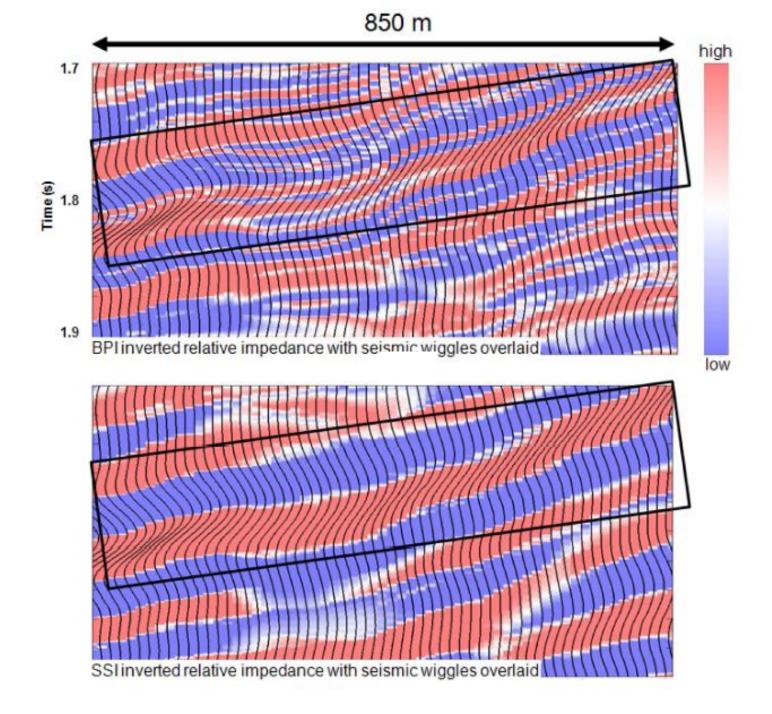
residual : True reflection coefficients - inverted reflection coefficients

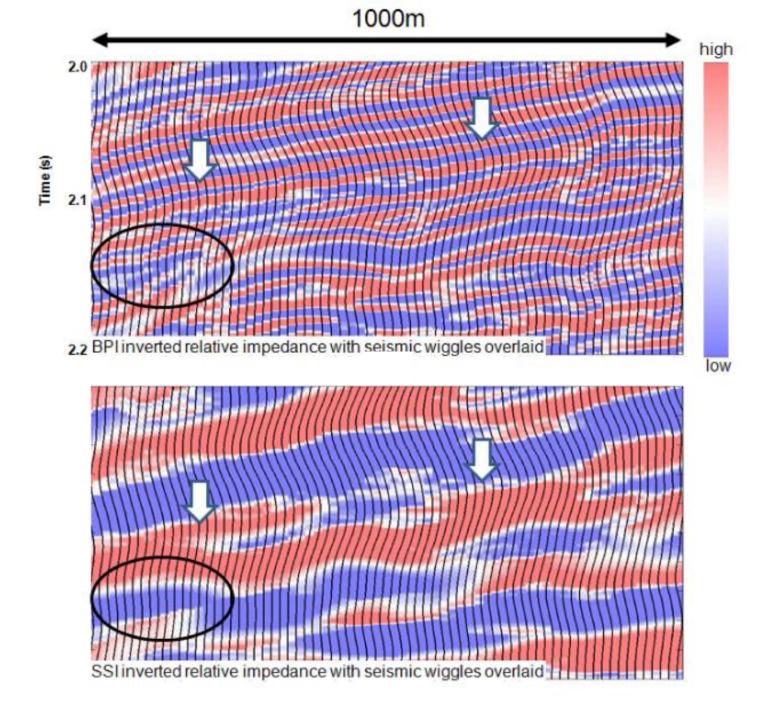


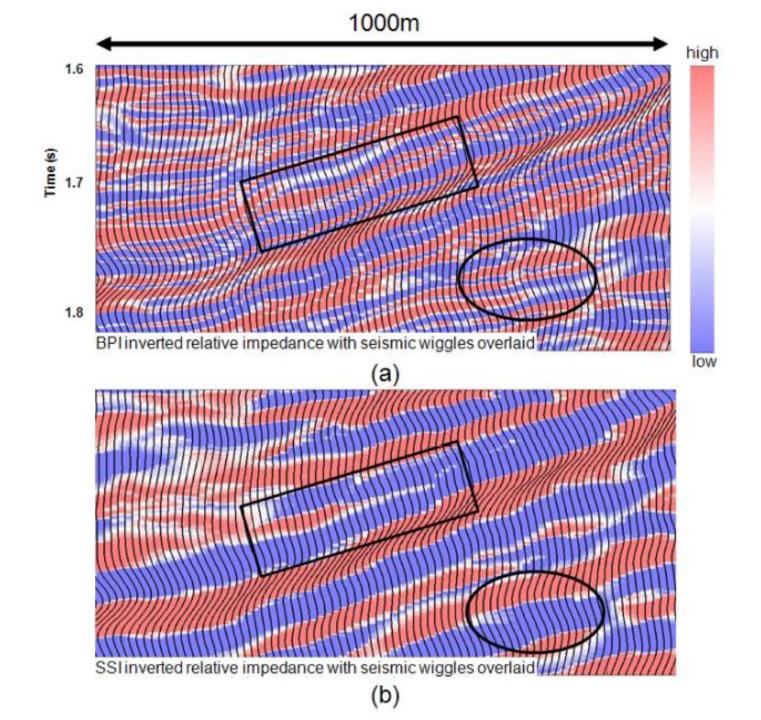
Real Data Example



: Well-log location







Conclusions

•Sparse-layer inversion can be accomplished by basis pursuit of a dictionary of functions representing thin-bed reflectivity patterns.

•This method determines a sparse number of thin-layer responses that sum to form the seismic trace.

•Synthetic tests indicate that sparse-layer inversion using basis pursuit (BPI) can better resolve thin beds than a comparable sparse-spike inversion (SSI) and usually correlates better to known reflectivity when optimal regularization parameters are used for both methods.